

Appl. No.: 10/759,481

Amdt. dated: 02/16/2007

Reply to Office action of: 09/18/2006

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Claim 1 (currently amended): A probe station for testing a device under test, said probe station comprising:

- (a) a first platen supporting an electrical probe engageable with a first surface of said device under test;
- (b) a chuck supporting said device under test;
- (c) a second platen having a top surface supporting thereon an optical probe for testing optical components on said device under test to emit light for impingement on said device under test and, alternatively, to detect light emitted by said device under test, said light propagating on an axis not substantially normal to said first surface;
- (d) said first platen positioned above said second platen and ~~said second platen positioned above said device under test;~~
- (e) at least 70% of the top surface of said second platen terminating in free space when said optical probe is not supported thereon.

Claim 2 (Original): The probe station of claim 1 wherein at least 80% of the top surface of said second platen terminating in free space when said optical probe is not supported thereon.

Claim 3 (currently amended): The probe station of claim 1 wherein said first platen ~~and said second platen are capable of~~ is supported for relative movement with respect relative to one another said second platen.

Claim 4 (Original): The probe station of claim 1 wherein at least 85% of the top surface of said second platen terminating in free space when said optical probe is not supported thereon.

Claim 5 (Original): The probe station of claim 1 wherein at least 90% of the top surface of said second platen terminating in free space when said optical probe is not supported thereon.

Appl. No.: 10/759,481

Amdt. dated: 02/16/2007

Reply to Office action of: 09/18/2006

Claim 6 (Original): The probe station of claim 1 wherein at least 95% of the top surface of said second platen terminating in free space when said optical probe is not supported thereon.

Claim 7 (Original): The probe station of claim 1 wherein said second platen has a greater top surface area than said first platen.

Claim 8 (Original): The probe station of claim 1 wherein said second platen has a smaller top surface area than said first platen.

Claim 9 (Previously presented): The probe station of claim 1 wherein said second platen has the same surface area as said first platen.

Claim 10 (Original): The probe station of claim 1 wherein said first platen is maintained in position with respect to said second platen by gravity such that if said probe station were turned upside down said first platen would freely fall away from said second platen.